集成电路自动化设计方法 (Design Automation of VLSI) 2015-秋季学期

电子科学与技术系:陈松 2015年9月10日

Course Webpage:

http://staff.ustc.edu.cn/~songch/da-ug.htm



Terminologies

- EDA (Electronic Design Automation)
 - 电子设计自动化
 - Synopsys, Cadence, Mentor Graphics, Agilent, etc.
- VLSI CAD (Very Large Scale Integration Computer-aided Design)
 - 超大规模集成电路计算机辅助设计
- IC CAD (Integrated Circuit Computer-aided Design)
 - 集成电路计算机辅助设计



- Course Overview
 - Contents
 - Evaluation
 - Course information
- History of Integrated Circuits



Course Info

- Name: Design Automation of VLSI (集成电路自动化设计方法)
- Teacher: 陈松 songch@ustc.edu.cn, 3A303, Thursday 3,4
 - Tel: 63602675 Mobile: 13155167790
- Text books
 - Lecture Notes
 - Wang, Chang, and Cheng (Ed.), *Electronic Design Automation: Synthesis, Verification, and Test*, Morgan Kaufmann, 2009.
 - Meil H. E. Weste and David Money Narris, CMOSVLSI Design: A circuits and Systems Perspective, fourth edition, Addison-Wesley, 2011.
 - David A. Patterson and John L. Hennessy, **Computer Organization and Design: The hardware/software interface**, 4th edition, Appendix C, Chapter 3, Chapter 4.

Available on the following webpage:

• http://staff.ustc.edu.cn/~songch/da-ug.htm

What

- Design methodology
 - Standard Cell / IP (Intellectual Property), FPGA, PLA
- Design Metrics
 - Power, Performance, Area, etc.
- Logic Design (Logic Synthesis)
 - Front-end design: From RTL to Logic Gates
- Physical Design (Physical Synthesis, Layout)
 - Back-end design: From Gates to GDSII
- Labs (Begin at the third week)
 - Verilog Hardware Description Language Basics
 - Synopsys Tool Suits: vcs, design compiler/power compiler/primetime, ICC compiler



- EDA Tool Designers
 - Basic requirements
- Theoretical guide for problem solving in using VLSI design tools
- VLSI System Architecture Designers
 - Coupling the front-end design and back-end design to shorten the design cycle and improve the chip performance
 - Complex multiplexer structures often cause congestion problem



Grading Policy

- Lecture Attendance: 10%
- Lab attendance: 50%
- Homework: 40%

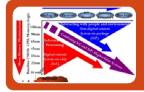




集成电路



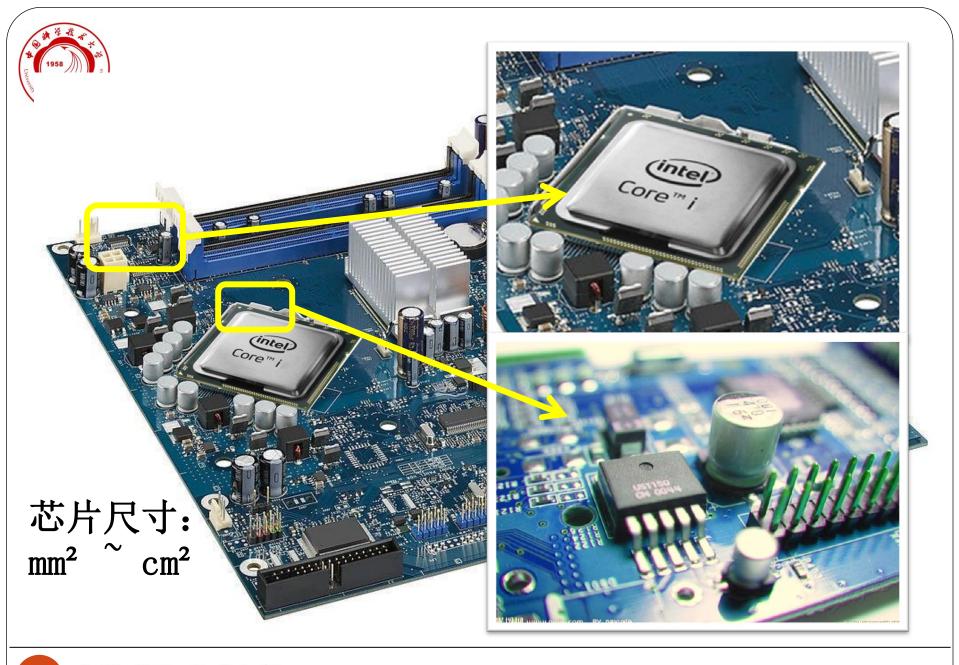
Golden Moore & Von Neumann



纳米电子时代的挑战



集成电路设计





晶体管



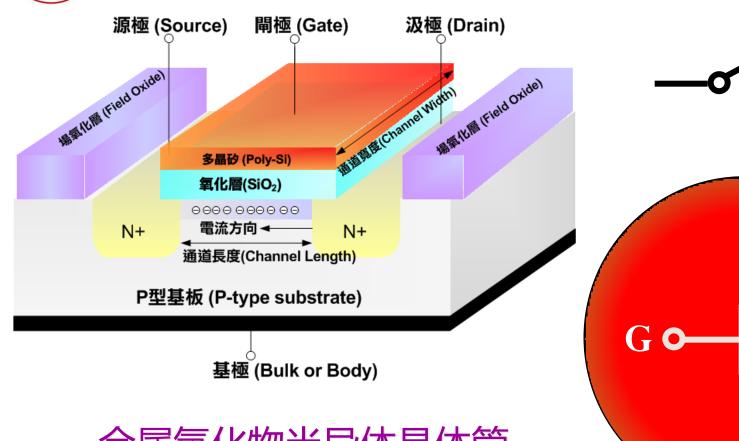
1947年,第一支晶体管在美国贝尔实验室诞生,**肖克利、巴丁**和布拉顿获得1956年诺贝尔物理学奖



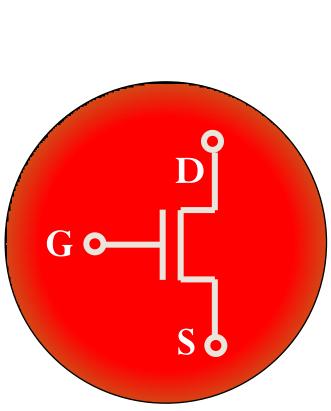
W. Shockley, J. Bardeen and W. Brattain



半导体晶体管

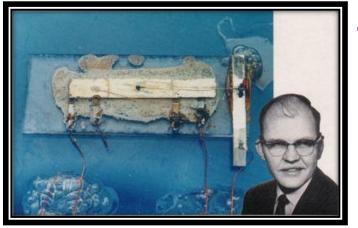








集成电路

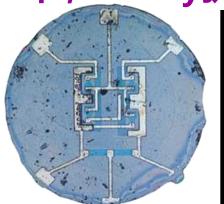


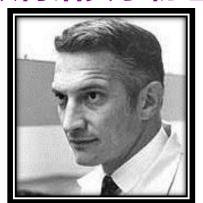
1958年,Jack S. Kilby 发明了集成电路的雏型



Pentium IV

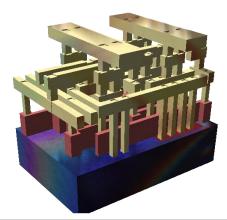






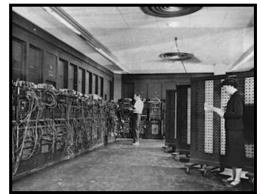
1959年,R. Noyce 发明了今天的集成电路







计算机的演变



ENIAC: 1945年第一台电子计算机诞生,它使用18000只电子管,70000只电阻,500万个焊点,耗电160千瓦,占地170平方米,重30吨,运算速度5000次/秒



P4004: 1971年世界 上第一个微处理器 在英特尔公司诞生

TRADIC: 1954年第一台晶体管计算机在贝尔实验室 诞生,它使用800只晶体管



IBM360:1964年第一台集成电路 计算机在IBM公司诞生,共6个型 号,兼顾了科学计算和事务处理 两方面的应用,各种机器全都相 互兼容。它的研制开发经费高达 50亿美元,是研制第一颗原子弹 的曼哈顿计划的2.5倍。

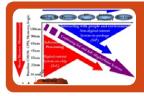




集成电路



Golden Moore & Von Neumann



纳米电子时代的挑战



集成电路设计

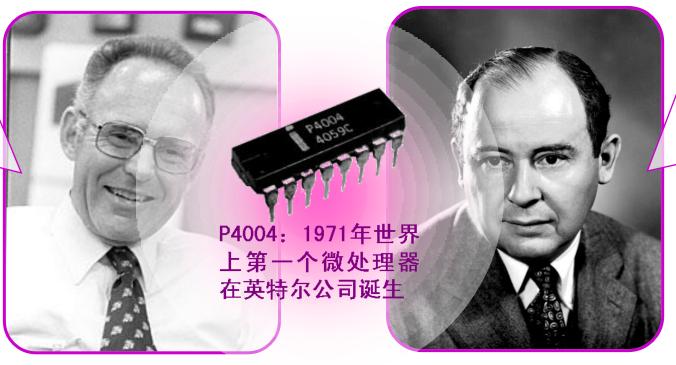


戈登·摩尔 和 约翰·冯·诺依曼

Golden Moore

Von Neumann

按比例缩小



冯·诺依曼 体系结构

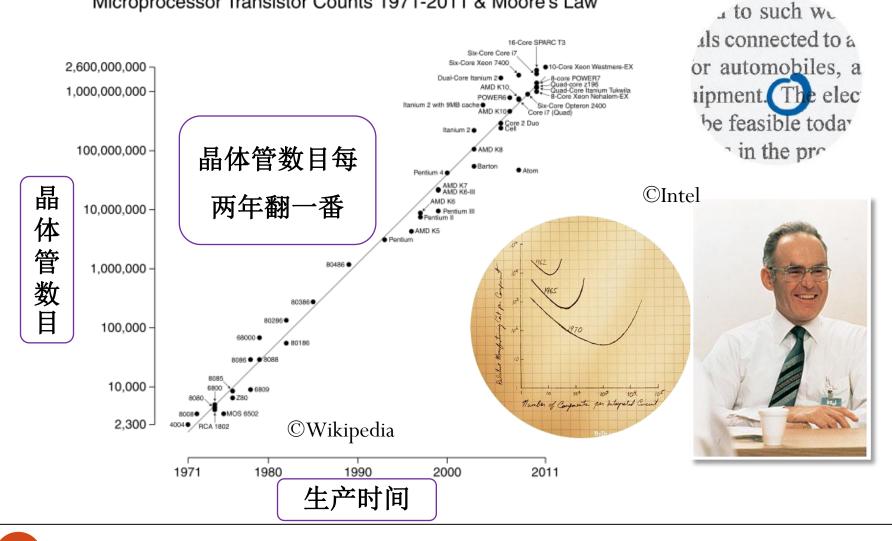
半导体

计算机



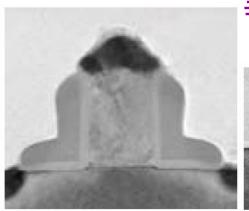
摩尔定律

Microprocessor Transistor Counts 1971-2011 & Moore's Law

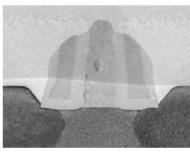




等比例缩小 (Scaling Down)



等比例缩小的半导体晶体管



©Kelin, Intel



130nm

90nm

65nm

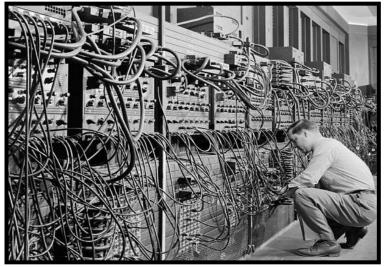
45nm

32nm

- 等比例缩小是地将一组硅器件的技术参数(通常多余20个)同步缩小
- 摩尔定律讲的是技术密度
- 摩尔定律是对集成电路产业的预测
- 等比列缩小是实现摩尔定律的方法



ENIAC: 专用计算机



ENIAC运行时,安排了一批年轻的女性工作人员按照计算要求插拔众多的接头,以实现不同的运算。工作十分繁琐,出错概率很大,效率很低。硬件的准备时间大大超过实际的计算所需的时间。

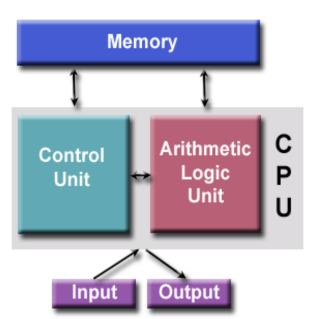
ENIAC是一台专为美国军方计算 火炮弹道轨迹设计的专用计算机。 虽然具备一定的编程能力,但程 序是事先预置好的。改变程序就 要求工作人员改变硬件的连线结 构。严格意义上讲,ENIAC不是 一台通用计算机。





冯-诺依曼体系结构







数字计算机的数制采用二进制;

计算机应该按照程序顺序执行

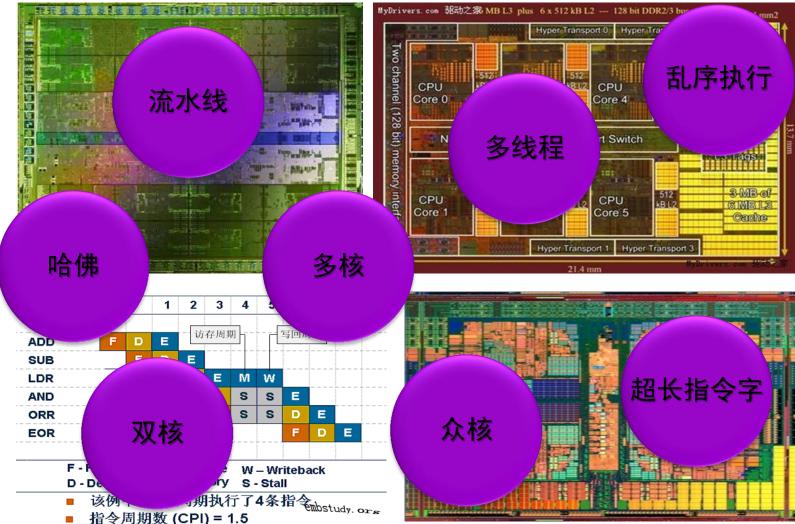
计算机:控制器、运算器、存储器、输入设备、输出设备;

从ENIAC到当前最先进的计算机都采用的是冯诺依曼体系结构。



原因之二:计算(Computation)

各种不同的体系结构



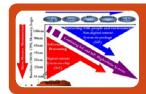




集成电路



Golden Moore & Von Neumann



纳米电子时代的挑战



集成电路设计

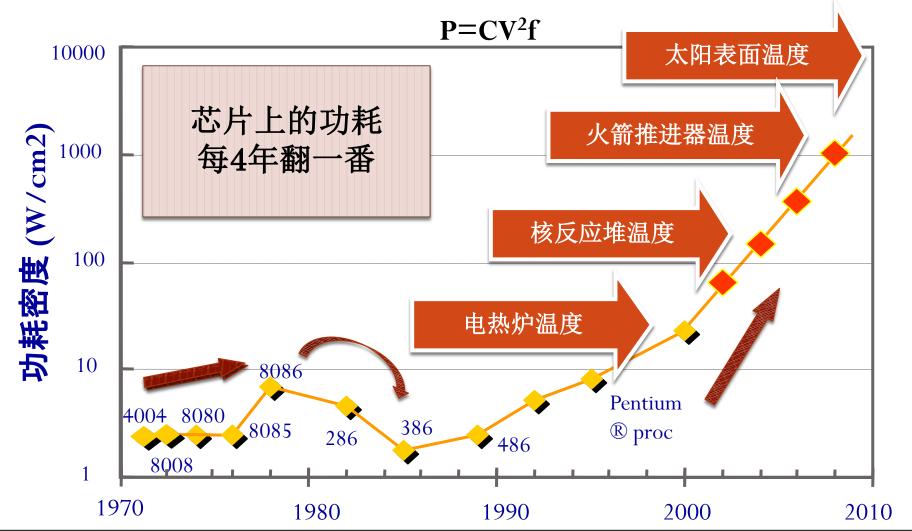


传统半导体行业



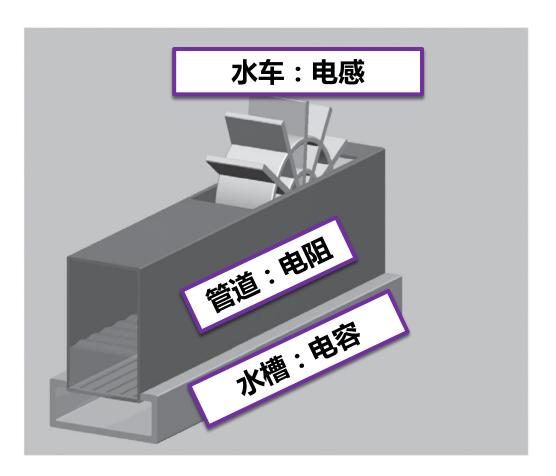


功耗是最关键问题





导线延时 (Wire Delay)



金属线变细:

电阻 R 🦯

电容C

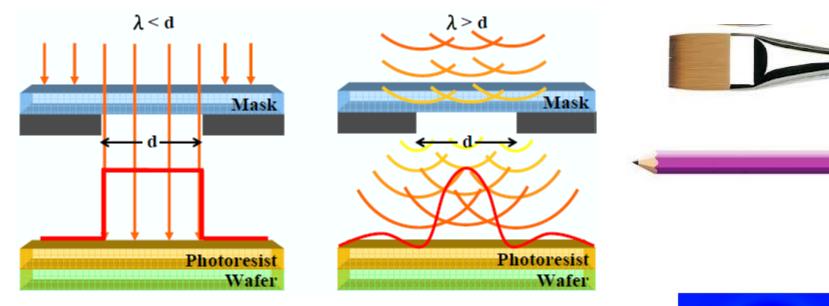
延时 $D = R \times C$

1 1

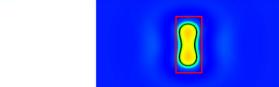
电阻增大速度远大于电 容减少速度!



可制造性问题



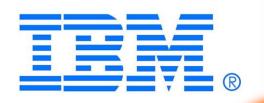
- 良片率
- 193nm vs. 40nm, 28nm, 16nm
 - OPC(光学邻近校正技术), Multiple Patterning Lithography
- 极紫外光刻 (10+nm)







大公司的游戏



16nm 12-15B\$



22nm 8-10B \$



32nm 5-7B\$





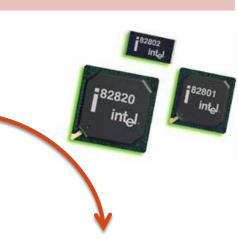
45nm 3.5-5B \$



现代半导体行业



技术、器件和电路创新,系统集成



投资

超越摩尔定律

功能增强 和/或 成本更低



市场增长





摩尔定律继续

摩尔定律的延续

超越摩尔定律:多样化

模拟/射频

无源

高压功率

传感器 促动器

生物芯片

130nm

90nm

65nm

45nm

32nm

22nm

16 nm/

教学部分与主教学部分特合:展高所信! 非数字部分:

数字部分:

信息处理

超越 CMOS



Technology Trends

- Advanced lithography methods needed to continue shrinking chip geometries
- New interconnect schemes
- Strain engineering for improved performance and lower power consumption
- 3D integration
- Novel transistor structures
- Migration to larger wafers

Major Process Technology Innovations Are Piling Up

EUV Lithography
Air Gaps
Thru-Silicon Vias
ETSOI (or FD-SOI)
Multi-Gate Transistors
DP and Inverse Lithography
Metal Gates/High-K Gate Oxides

Nanocarbon Technologies Ge and/or III-V Channels

> In the 2000s and 2010s, the industry is being forced to adopt many major innovations in process technology.

Low-K Insulators Strain Engineering SiGe

2020

2010

2000

1990

1970

1960

Silicon-on-Insulator Copper Interconnects

Immersion Lithography

Deep UV Lithography Step-and-Scan Lithography

CMP and STI Multiple Metal Layers

Step-and-Repeat Lithography Projection Printing

Ion Implantation

Surface Passivation CMOS Architecture MOSFET Planar Process Oxide Masking In the 1970s, 1980s, and 1990s, there were only one or two major process technology advancements in each decade.

In the early years, one would expect several significant advancements and innovations.

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Source: IC Insights

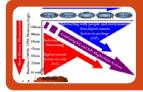




集成电路



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纳米电子时代的挑战



集成电路设计



Integrated Circuits Industry

Design(设计)

Tools & IP: Synopsys, Cadence, Mentor Graphics, etc. Fabless: Qualcomm, MediaTek, Huawei (华 为), Xilinx, Altera, Spreadtrum (展讯), etc.



Lithography Instruments: ASML, NEC, etc.

Foundries: TSMC, UMC, GF, Intel, Samsung, SMIC (中芯国际)



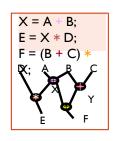
Packaging & Testing (封装与测试)

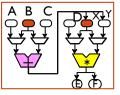
Testing Instruments: Agilent (安捷 伦), Rohde&Schwarz

ASE Global, Amkor, etc.

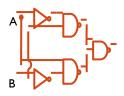


ASIC (专用集成电路)





Adder I Multiplier I Register 8 Multiplexer 4





System/Behavioral Descriptions

High-level Synthesis

Register Transfer Level Descriptions

Logic Synthesis

逻辑综合

高层次综合

Gate Level Netlist

Physical Synthesis

物理综合/ 芯片布图

Design Automation

Scheduling; Binding;

Allocation.

Logic

Optimization

Technology

Mapping.

Floorplanning;

Placement;

Routing;

etc.

Layout mask



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High-level Synthesis (高层次综合)

- Transformation from a behavioral specification of a system to its RTL structure specification
 - E.g., from C/C++ to RTL, Bluespec, Xilinx AutoESL
 - Promote the productivity
 - Essential tasks: scheduling, binding, allocation

```
begin
  done = 0; A = inA; B = inB;
  while (!done)
  begin
  if (A < B)
    swap = A;
    A = B; B = swap;
  else if (B!=0)
    A = A - B;
  else
    done = 1;
end</pre>
```



Logic Synthesis (逻辑综合)

- Transformation from a Register-Transfer-Level (RTL) description to a gate-level netlists
 - Hardware Description Language
 - Verilog HDL, VHDL
 - Logic Optimization
 - Technology Mapping



Physical synthesis(物理综合)

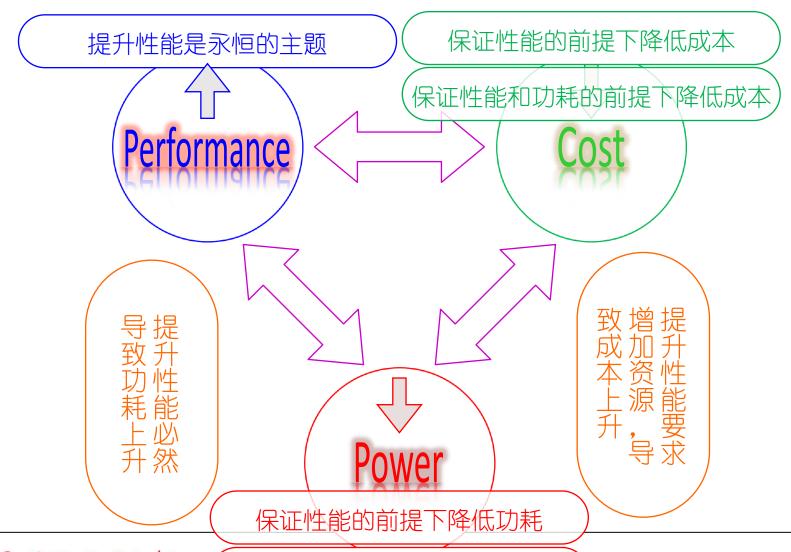
- Transformation from a gate-level netlists to its physical layouts (masks)
 - Partitioning (划分)
 - Floorplanning (布图规划)
 - Power/Ground Network Synthesis (电源线/地线网络合成)
 - Placement (布局)
 - Routing (布线): Clock Tree, Signal, Power/Ground
 - Post-routing (后布线优化)
 - Redundant Via Insertion (Design for Yield)
 Large Scale Discrete Optimization Problems:

Computation-Consuming.

How to find good solutions in acceptable time?



Performance, Power, Cost



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保证性能和成本的前提下降低功耗



Modern Chip (VLSI) Design

- Managing Design Complexity (设计复杂性)
 - System-on-Chip: IP reuse, Platform-based Design Methodology
 - Electronic System Level Synthesis (High-level synthesis)
 - Raising the design abstraction
- Power (功耗)
 - Low Power Technologies: LeakagePower, Dynamic Power
 - New Device: FinFET
- Interconnect (互连)
 - Delay, System-level design & Physical Design
 - Network-on-Chip
 - 3D ICs
 - Optical-/wireless-/CNT-/RF Interconnect
- Reliability (可靠性)
- Design For Manufacturability: EUV, OPC, PSM, ...